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FOUR DIGIT LED DISPLAY (0.39 Inch)

LFD435/63-XX

DATA SHEET

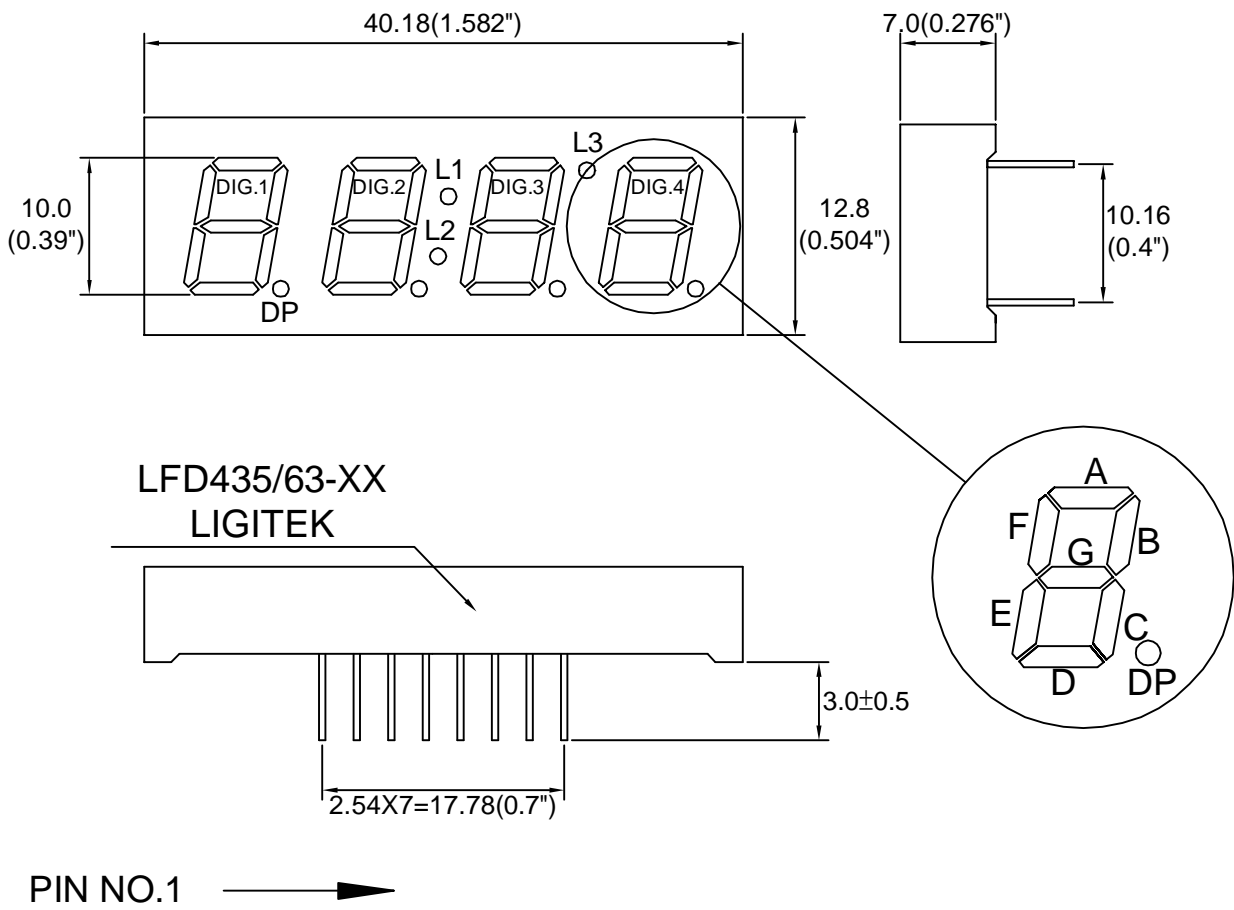
DOC. NO : QW0905-LFD435/63-XX

REV. : A

DATE : 26 - Sep. - 2005



Package Dimensions



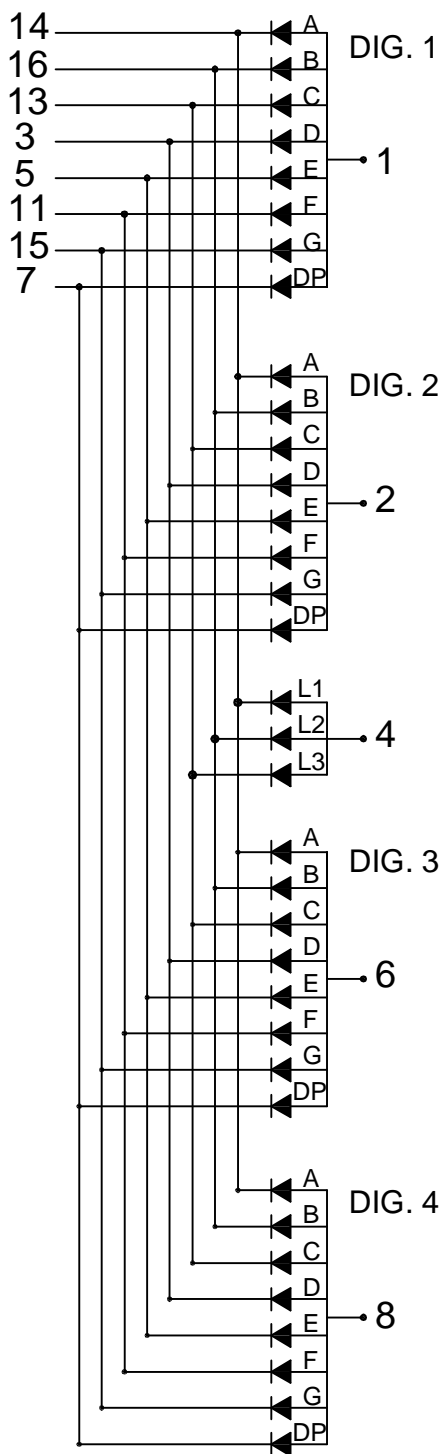
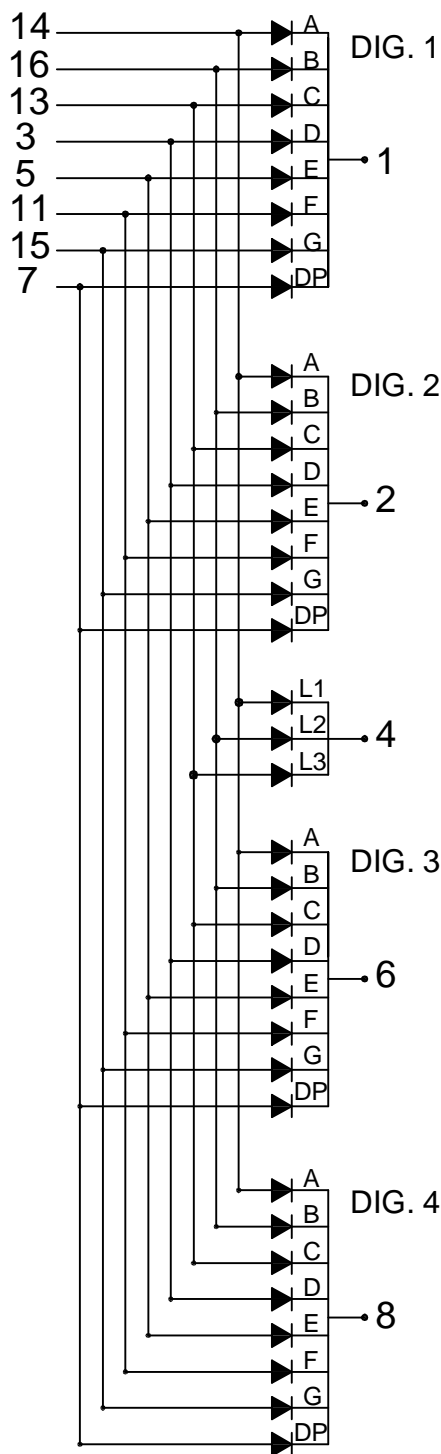
Note : 1.All dimension are in millimeters and (Inch) tolerance is $\pm 0.25\text{mm}$ unless otherwise noted.
2.Specifications are subject to change without notice.



Internal Circuit Diagram

LFD4353-XX

LFD4363-XX



**Electrical Connection**

PIN NO.1	LFD4353-XX	PIN NO.1	LFD4363-XX
1	Common Cathode Dig.1	1	Common Anode Dig.1
2	Common Cathode Dig.2	2	Common Anode Dig.2
3	Anode D	3	Cathode D
4	Common Cathode L1,L2,L3	4	Common Anode L1,L2,L3
5	Anode E	5	Cathode E
6	Common Cathode Dig.3	6	Common Anode Dig.3
7	Anode DP	7	Cathode DP
8	Common Cathode Dig.4	8	Common Anode Dig.4
9	NC	9	NC
10	NO PIN	10	NO PIN
11	Anode F	11	Cathode F
12	NO PIN	12	NO PIN
13	Anode C,L3	13	Cathode C,L3
14	Anode A,L1	14	Cathode A,L1
15	Anode G	15	Cathode G
16	Anode B,L2	16	Cathode B,L2

**Absolute Maximum Ratings at Ta=25 °C**

Parameter	Symbol	Ratings	UNIT
		Y	
Forward Current Per Chip	IF	20	mA
Peak Forward Current Per Chip (Duty 1/10,0.1ms Pulse Width)	IFP	80	mA
Power Dissipation Per Chip	PD	60	mW
Reverse Current Per Any Chip	Ir	10	μA
Operating Temperature	ToPr	-25 ~ +85	°C
Storage Temperature	Tstg	-25 ~ +85	°C
Solder Temperature 1/16 Inch Below Seating Plane For 3 Seconds At 260 °C			

Part Selection And Application Information(Ratings at 25°C)

PART NO	CHIP		common cathode or anode	λ P (nm)	Δ λ (nm)	Electrical					IV-M
	Material	Emitted				Vf(v)			Iv(mcd)		
						Min.	Typ.	Max.	Min.	Typ.	
LFD4353-XX	AlGaInP	Yellow	Common Anode	585	35	1.7	2.1	2.6	1.0	1.75	2:1
LFD4363-XX			Common Cathode								

Note : 1.The forward voltage data did not including ±0.1V testing tolerance.
2. The luminous intensity data did not including ±15% testing tolerance.

**Test Condition For Each Parameter**

Parameter	Symbol	Unit	Test Condition
Forward Voltage Per Chip	V _f	volt	I _f =20mA
Luminous Intensity Per Chip	I _v	mcd	I _f =10mA
Peak Wavelength	λP	nm	I _f =20mA
Spectral Line Half-Width	$\Delta \lambda$	nm	I _f =20mA
Reverse Current Any Chip	I _r	μA	V _r =5V
Luminous Intensity Matching Ratio	IV-M		



Typical Electro-Optical Characteristics Curve

Y CHIP

Fig.1 Forward current vs. Forward Voltage

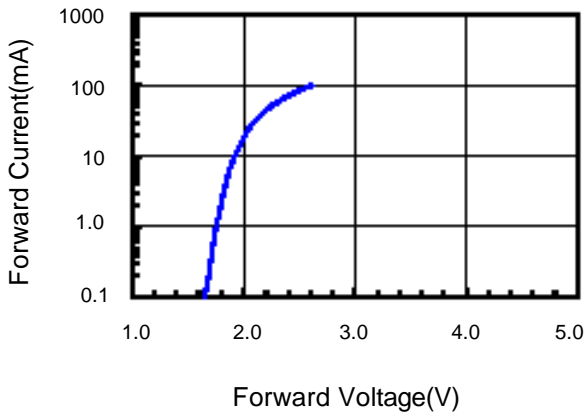


Fig.2 Relative Intensity vs. Forward Current

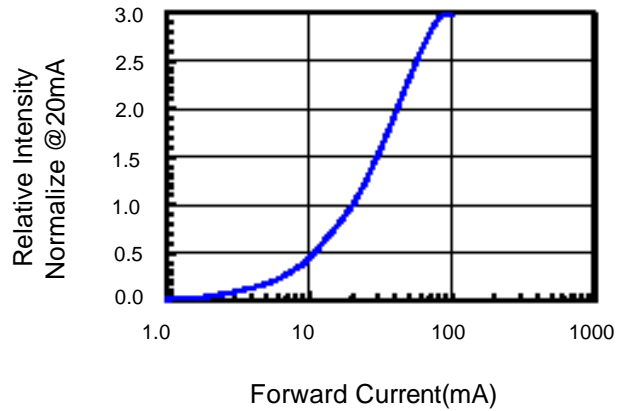


Fig.3 Forward Voltage vs. Temperature

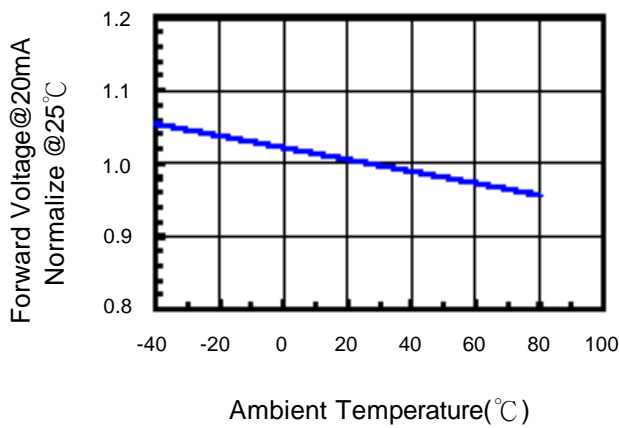


Fig.4 Relative Intensity vs. Temperature

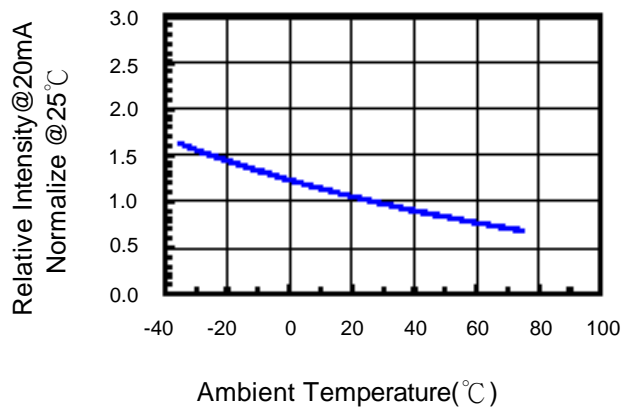
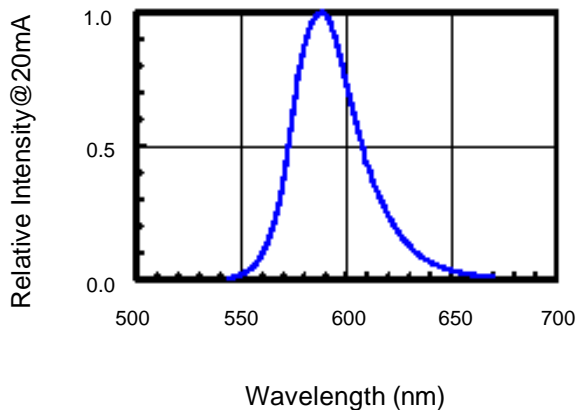


Fig.5 Relative Intensity vs. Wavelength





Reliability Test:

Test Item	Test Condition	Description	Reference Standard
Operating Life Test	1.Under Room Temperature 2.If=10mA 3.t=1000 hrs (-24hrs, +72hrs)	This test is conducted for the purpose of determining the resistance of a part in electrical and thermal stressed.	MIL-STD-750: 1026 MIL-STD-883: 1005 JIS C 7021: B-1
High Temperature Storage Test	1.Ta=105 °C±5°C 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of high temperature for hours.	MIL-STD-883:1008 JIS C 7021: B-10
Low Temperature Storage Test	1.Ta=-40 °C±5°C 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of low temperature for hours.	JIS C 7021: B-12
High Temperature High Humidity Test	1.Ta=65 °C±5°C 2.RH=90%~95% 3.t=240hrs ±2hrs	The purpose of this test is the resistance of the device under tropical for hours.	MIL-STD-202:103B JIS C 7021: B-11
Thermal Shock Test	1.Ta=105 °C±5°C & -40 °C±5°C (10min) (10min) 2.total 10 cycles	The purpose of this is the resistance of the device to sudden extreme changes in high and low temperature.	MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1011
Solder Resistance Test	1.T.Sol=260 °C±5°C 2.Dwell time= 10 ±1sec.	This test intended to determine the thermal characteristic resistance of the device to sudden exposures at extreme changes in temperature when soldering the lead wire.	MIL-STD-202: 210A MIL-STD-750: 2031 JIS C 7021: A-1
Solderability Test	1.T.Sol=230 °C±5°C 2.Dwell time=5 ±1sec	This test intended to see soldering well performed or not.	MIL-STD-202: 208D MIL-STD-750: 2026 MIL-STD-883: 2003 JIS C 7021: A-2